

<b>Notice of References Cited</b>	Application/Control No. 10/052,511	Applicant(s)/Patent Under Reexamination NAGATA ET AL.	
	Examiner Albert W. Paladini	Art Unit 2125	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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	B	US-5,698,982	12-1997	Mitchell, William K.	324/339
	C	US-5,946,211	08-1999	Glover, Douglas Wade	700/97
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	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	IBM Technical Disclosure (NN9512237) Method for Modeling the Skin Effect in Inductance Calculations 12/1/95
	V	Lavers et al. IEEE Journal (7803-6667-0/01) Constriction Resistance at High Signal Frequencies. 2001.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.